



NABL

National Accreditation Board for Testing and Calibration Laboratories

Department of Science & Technology, India

CERTIFICATE OF ACCREDITATION

EMI/EMC TEST FACILITY, LINKWELL TELESYSTEMS PVT. LTD.

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2005

"General Requirements for the Competence of Testing & Calibration Laboratories"

for its facilities at

B-45, Electronic Complex, Kushaiguda, Hyderabad

in the field of

ELECTRICAL TESTING

(You may also visit NABL website www.nabl-india.org to view the scope of accreditation)

Certificate Number T-2166

Issue Date 09/03/2012



Valid Until 08/03/2014

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the additional requirements of NABL.

Signed for and on behalf of NABL

Bibin Philip
Convener

Anil Relia
Director

Dr. T. Ramasami
Chairman



रा.प्र.प्र.बो.

राष्ट्रीय परीक्षण और अंशशोधन
प्रयोगशाला प्रत्यायन बोर्ड
विज्ञान एवं प्रौद्योगिकी विभाग, भारत

प्रत्यायन प्रमाण-पत्र

ई एम आई/ई एम सी टेस्ट फेसिलिटी, लिंकवेल टेलीसिस्टम्स प्रा. लि.

का मूल्यांकन और प्रत्यायन निम्न मानक के अनुसार

आई.एस.ओ./आई.ई.सी. 17025:2005

“परीक्षण एवं अंशशोधन प्रयोगशालाओं की सक्षमता की सामान्य अपेक्षाएँ”

हैदराबाद

में स्थित इसकी सुविधाओं के लिए

विद्युत परीक्षण

के क्षेत्र में किया गया।

प्रमाण-पत्र संख्या प-2166

जारी करने की तिथि 09/03/2012



वैधता की तिथि 08/03/2014

यह प्रमाण-पत्र उपर्युक्त मानक तथा राष्ट्रीय परीक्षण और अंशशोधन प्रयोगशाला प्रत्यायन बोर्ड की अतिरिक्त अपेक्षाओं का निरंतर संतोषप्रद अनुपालन किए जाने पर अनुबंध में निर्दिष्टानुसार प्रत्यायन के क्षेत्र के लिए वैध रहेगा।

रा.प्र.प्र.बो. की ओर से हस्ताक्षरित

विविन फिलिप

विविन फिलिप
संयोजक

अनिल रेलिया

अनिल रेलिया
निदेशक

डा. टी. रामसामी

डा. टी. रामसामी
अध्यक्ष



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Department of Science & Technology, India

SCOPE OF ACCREDITATION

| | | | |
|------------------------|---|-------------|------------|
| Laboratory | EMI/EMC Test Facility, Linkwell Telesystems Pvt. Ltd., B- 45, Electronic Complex, Kushaiguda, Hyderabad | | |
| Accreditation Standard | ISO/IEC 17025: 2005 | | |
| Field | Electrical Testing | Issue Date | 09.03.2012 |
| Certificate Number | T-2166 | Valid Until | 08.03.2014 |
| Last Amended on | - | Page | 1 of 2 |

| S.No. | Product / Material of Test | Specific Test Performed | Test Method Specification against which tests are performed | Range of Testing / Limits of Detection |
|--------------------------------|--------------------------------------|---|---|---|
| <u>EMI/ EMC TESTING</u> | | | | |
| 1. | All Electrical & Electronic products | Electrostatic Discharge Immunity | IEC 61000 4-2: 2001-04 IS 13779: 1999 | Pulse Amplitude: ± 2kV to ± 15 kV Contact & Air Discharge |
| | | Radiated, Radio-Frequency electromagnetic field immunity (Radiated Susceptibility) | IEC 61000-4-3: 2002-09 | Frequency Range: 80MHz to 1GHz Field Strength: 1V/m to 10V/m |
| | | Electrical Fast Transient Burst | IEC 61000-4-4: 2004-07 | Pulse Amplitude: ± 0.5kV to ± 4 kV Burst Frequency: 5kHz |
| | | Surge Immunity | IEC 61000-4-5: 2005-11 | Surge Voltage: ± 0.5kV to ± 4 kV Pulse Shape : 1.2/50µs / 8/20µs |
| | | Immunity to conducted disturbances, induced by radio-frequency field (Conducted Susceptibility) | IEC 61000-4-6: 2004-11 | Frequency Range: 150kHz to 80 MHz Field Strength: 1V/m to 10V/m |
| | | Voltage Dips & Short Interruptions | IEC 61000-4-11: 2004-03 | Dips: 0 %, 40%, 70%, 80% |
| | | Conducted Emissions | CISPR 22: 2005 | Frequency: 150kHz to 30MHz Limits: Class A & Class B |
| | | Radiated Emissions | CISPR 22: 2005 | Frequency: 30MHz to 1GHz Limits: Class A & Class B |

Convenor



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|-------|----------------------------|-------------------------|---|--|
|-------|----------------------------|-------------------------|---|--|

ENVIRONMENTAL TESTING

| | | | | |
|----|--------------------------------------|--------------------------|--|---|
| 2. | All Electrical & Electronic products | Cold | IS 9000 (Part II)-1997 (Reaffirmed 2004) IEC 60068 2-1: 1990 IS 13779:1999 IEC 62052-2-11: 2003 | Temperature: -40°C to + 5°C |
| | | Dry Heat | IS 9000 (Part III)-1977 (Reaffirmed 2004) IEC 61000-2-2:2007 IEC 62052-2-11:2003 IS 13779:1999 | Temperature: 40°C to 175°C |
| | | Damp Heat (Cyclic) | IS 9000 (Part V)-1981 (Reaffirmed 2004) IEC 60068-2-30:2007 IEC 62052-2-11:2003 | Temperature: 40°C to 55°C RH: 95% |
| | | Damp Heat (Steady State) | IS 9000 (part IV)-2008 IEC 60068 -2-78:2001 | Temperature: 30°C/ 40°C RH: 85%/ 95% |
| | | Vibration (Sinusoidal) | IS 9000 (Part VIII)-1981 (Reaffirmed 2003) IEC 62052-11: 2003 IEC 60068-2-6: 2007 IS 13779:1999 | Frequency: 5Hz to 500 Hz Displacement Amplitude: 10mm Acceleration: 0.5 g to 10 g |
| | | Shock | IS 9000 (Part VII)-1979 IEC 60068-2-27: 2008 | Acceleration: 4000 m/s ² Pulse Shape: Half sine Pulse Duration: 0.5 ms to 11 ms |

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